S	eard	ch Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/619,626	TAKEUCHI ET AL.
Examiner	Art Unit
Omar F. Fernández Rivas	2129

SEARCHED			
Class	Subclass	Date	Examiner
706	1,12,14,16 45,50,935	11/1/2005	OFR
702	79,176	11/1/2005	OFR
702	181	11/1/2005	OFR
708	100	11/1/2005	OFR
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST-All databases -keywords: autoregressive, outlier, change,learning, training, variance, moving average	11/1/2005	OFR
Class 706 Subclases: 1,12,14,16,45,50,935 -Search limited as shown in attached documents	11/1/2005	OFR
Class 702 Subclasses: 79,176,181 -Search limited as shown in attached documents	11/1/2005	OFR
Class 708 Subclasses: 100 -Search limited as shown in attached documents	11/1/2005	OFR
Inventor Name Search -Bodin, William -Burkhart, Michael -Eisenhauer, Daniel -Schumacher, Daniel -Watson, Thomas	10/31/2005	OFR
IEEE Xplore Database -keywords: autoregressive model, outlier	10/31/2005	OFR
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